

Search Notes



Application/Control No.

10/007,196

Examiner

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Applicant(s)/Patent under Reexamination

HARTER ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	x 1	3/06	DN
	7	↓	↓
	8	↓	↓
	9	↓	↓
	10	↓	↓
	x 26	↓	↓
717	121	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	3/06	DN
1. PG Pub	↓	↓
2. Patent	↓	↓
II FOREIGN		
1. EPO		
2. JPO		
3. IBM-TDB		
4. Derwent	↓	↓